EE 330 Lecture 9

IC Fabrication Technology

- Crystal Preparation
- Masking
- Photolithographic Process
- Deposition
- Ion Implantation
- Etching
- Diffusion
- Oxidation
- Epitaxy
- Polysilicon
- Planarization
- Contacts, Interconnect and Metalization

Exam 1 Friday Sept 22
Exam 2 Friday Oct 20
Exam 3 Friday Nov. 17
Final Monday Dec 11 12:00 – 2:00 p.m.

Review from Last Time Design Rules

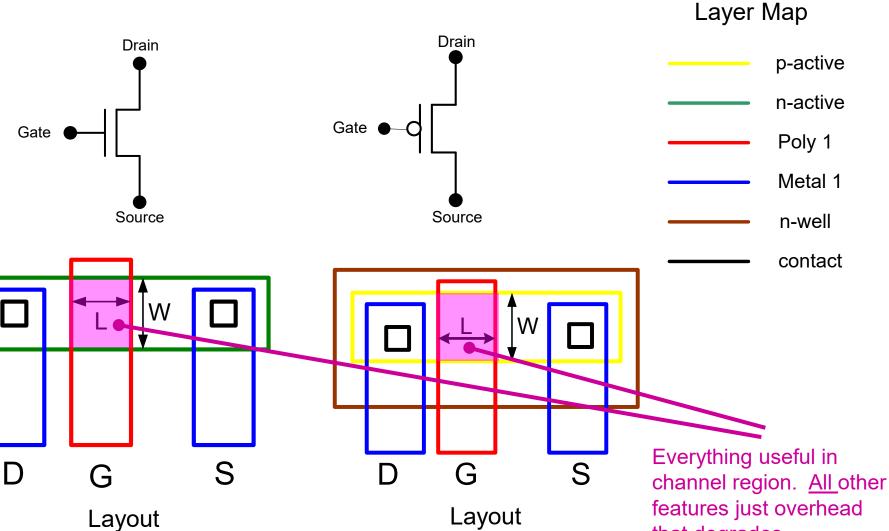
• Give minimum feature sizes, spacing, and other constraints that are acceptable in a process

• Very large number of devices can be reliably made with the design rules of a process

• Yield and performance unpredictable and often low if rules are violated

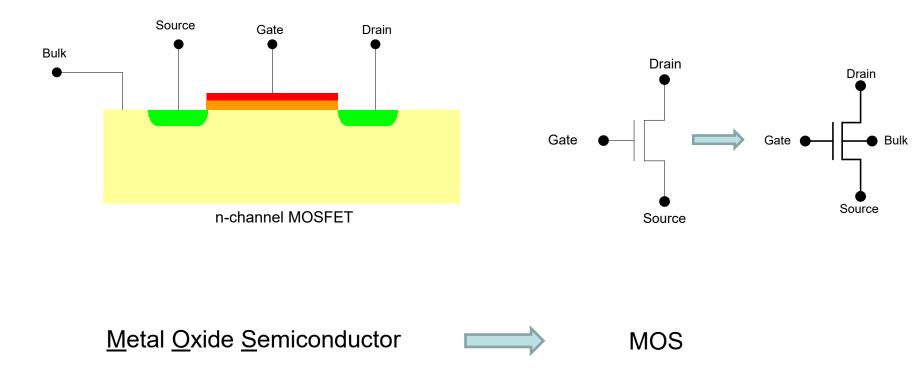
Compatible with design rule checker in integrated toolsets

Design Rules and Layout – consider transistors



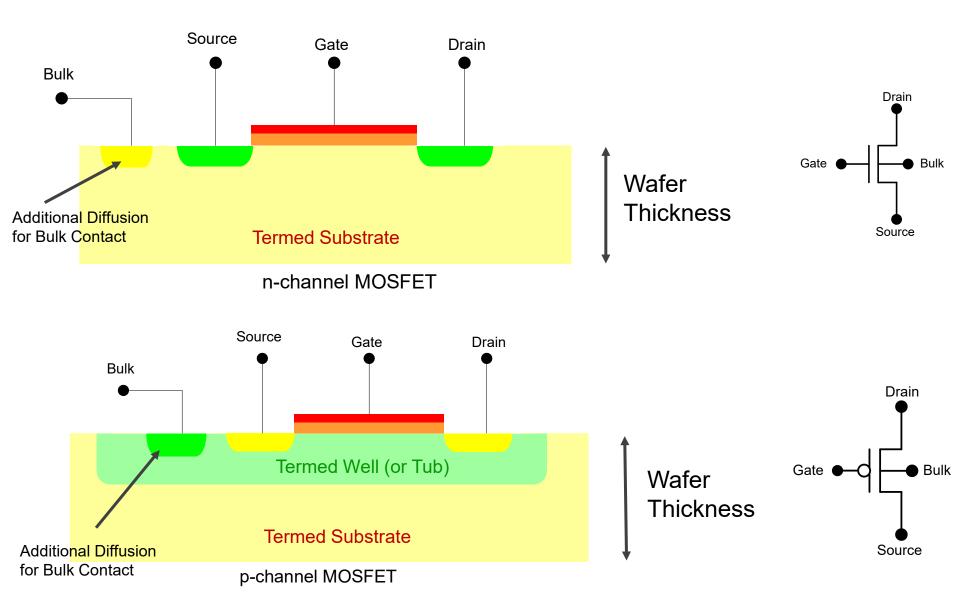
features just overh that degrades performance

Review from Last Time MOS Transistor Nomenclature

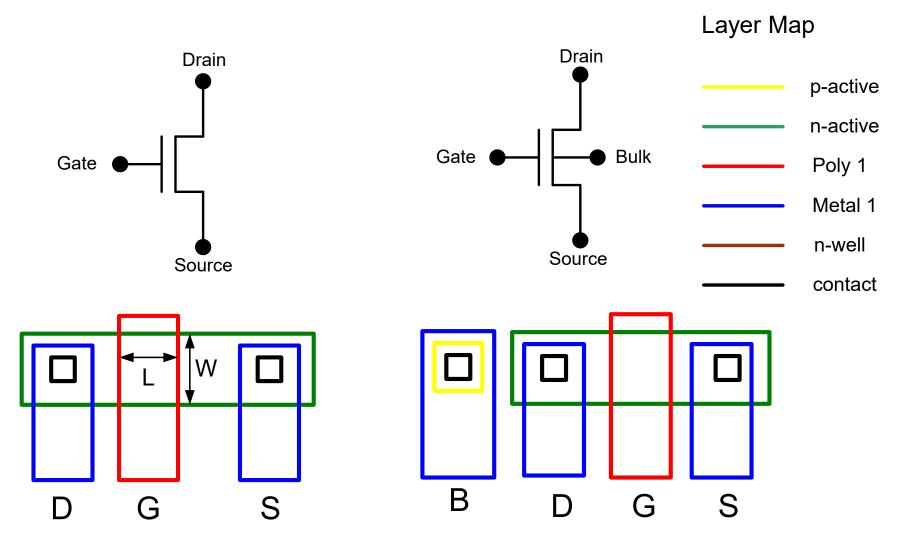


Early processes used metal for the gate, today metal is seldom used but the term MOS transistor is standard even though the gate is no longer metal

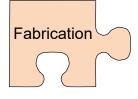
Review from Last Time MOS Transistor in Bulk CMOS Process



Design Rules and Layout – consider transistors



- Bulk connection needed
- Single bulk connection can often be used for several (many) transistors



Technology Files

Design Rules

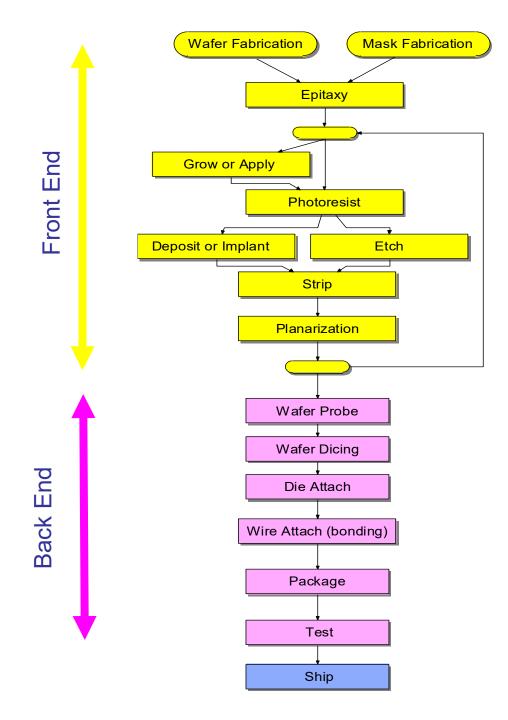
Process Flow (Fabrication Technology)

• Model Parameters (will discuss in substantially more detail after device operation and more advanced models are introduced)

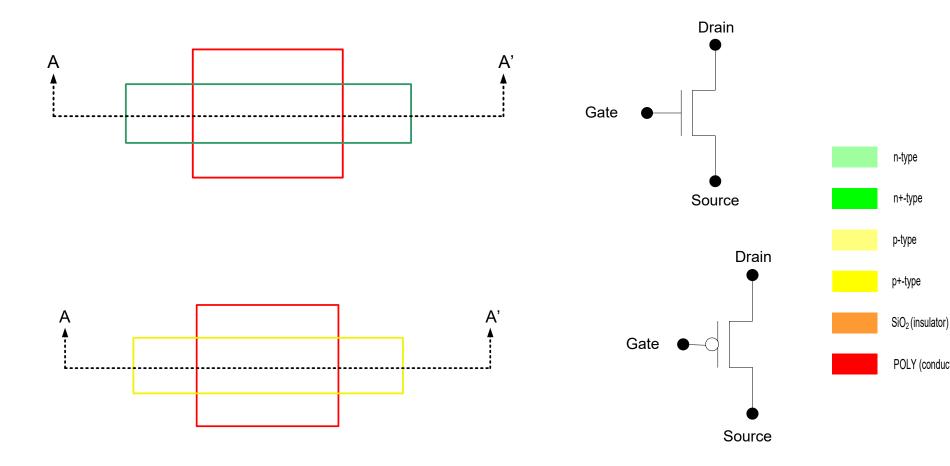
IC Fabrication Technology

See Chapter 3 and a little of Chapter 1 of WH

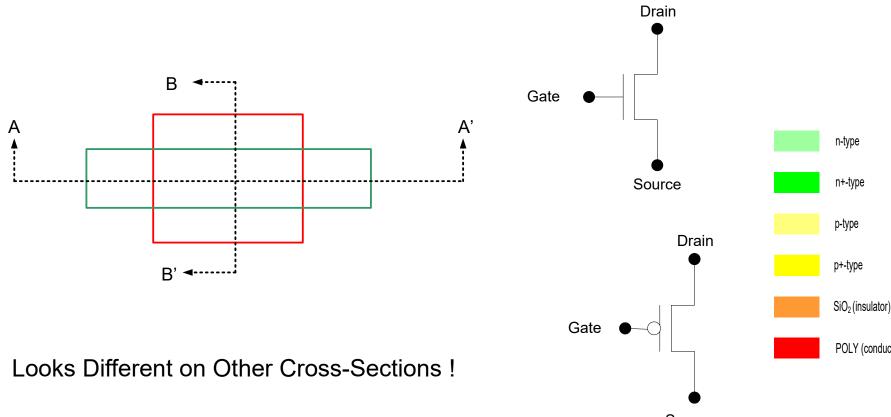
Generic Process Flow



First a bit of background on transistor structure

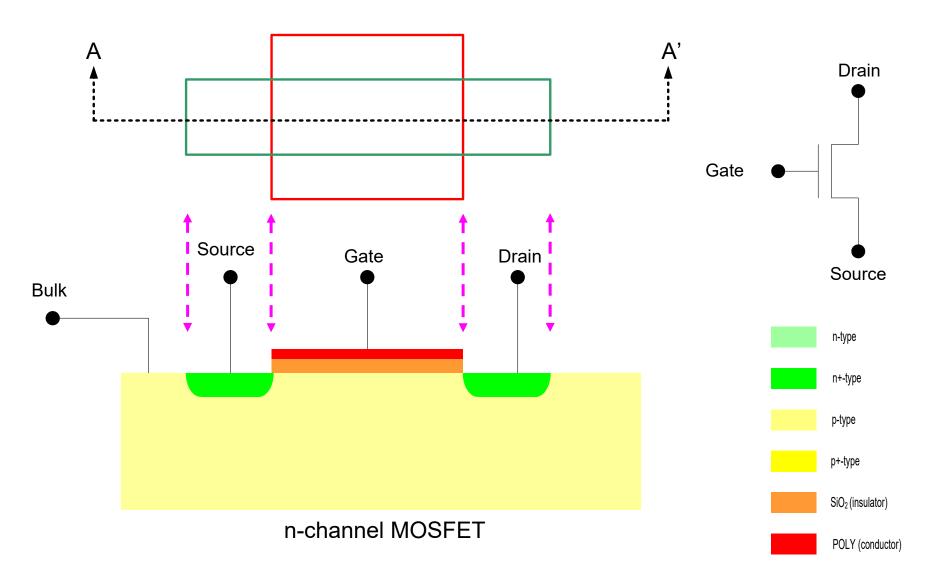


First a bit of background on transistor structure

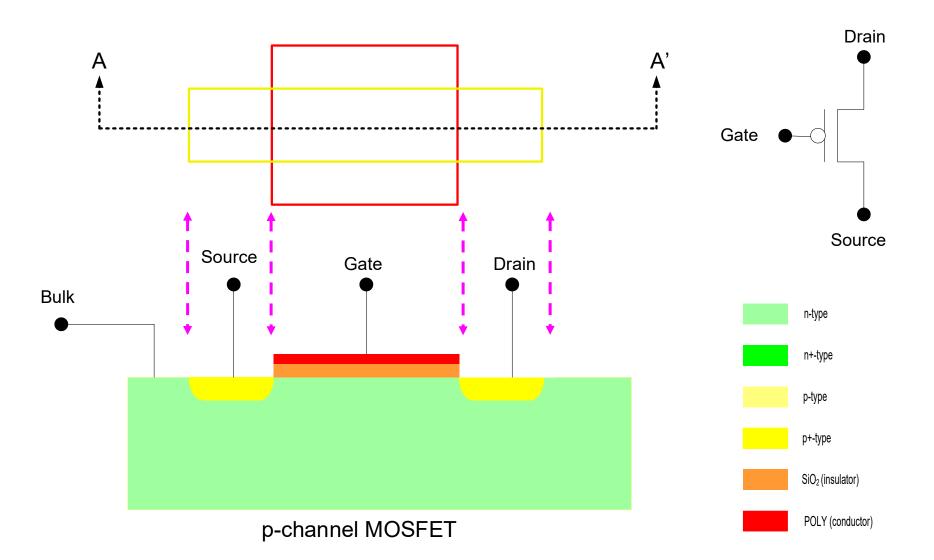


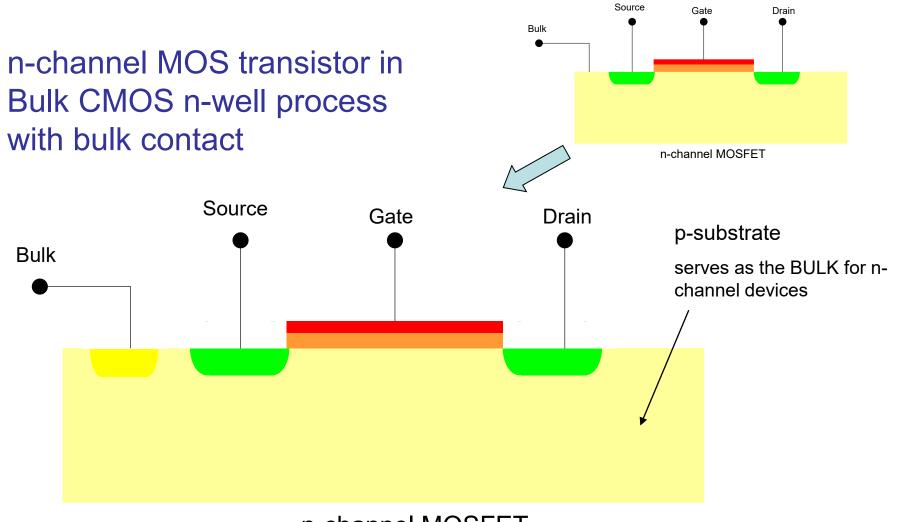
Source

Recall

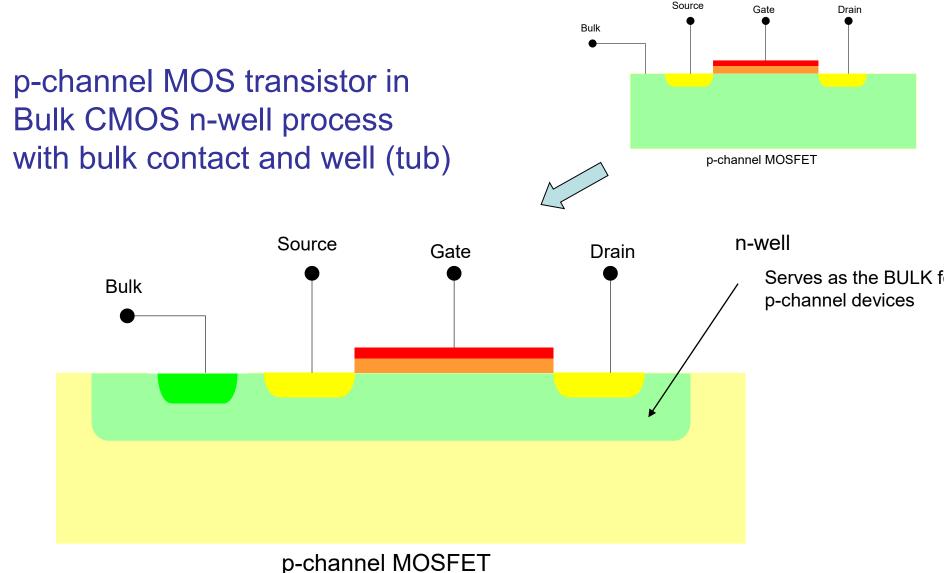


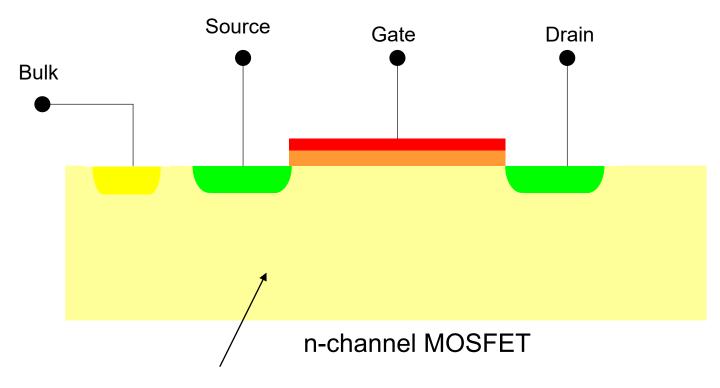
Review



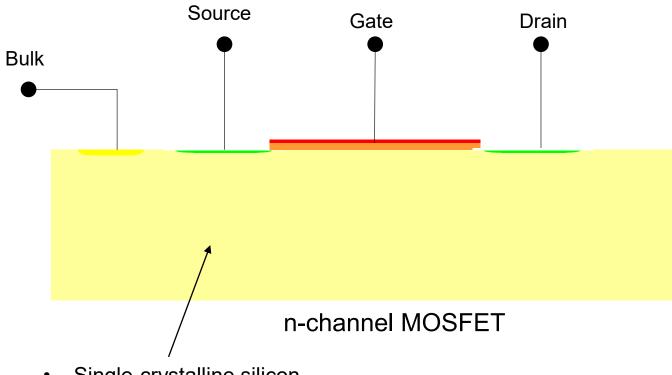


n-channel MOSFET

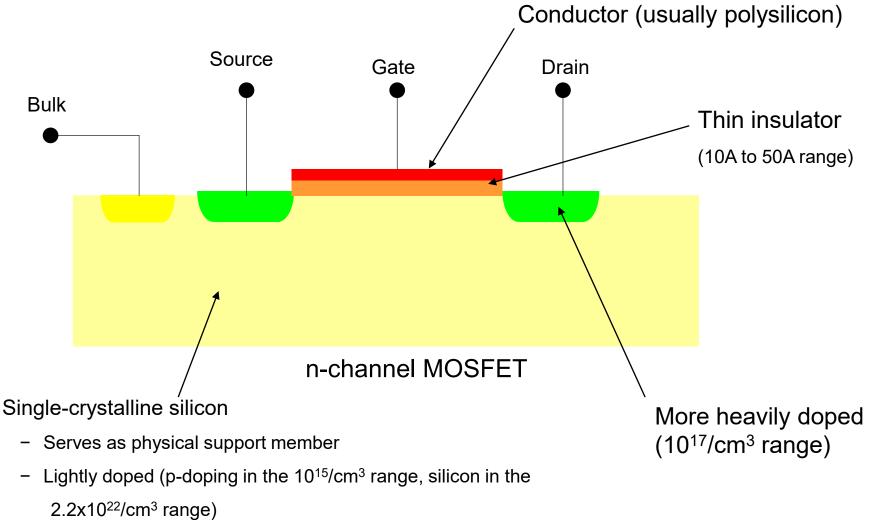




- Single-crystalline silicon
 - Serves as physical support member
 - Lightly doped
 - Vertical dimensions are not linearly depicted
 - Often termed the Bulk

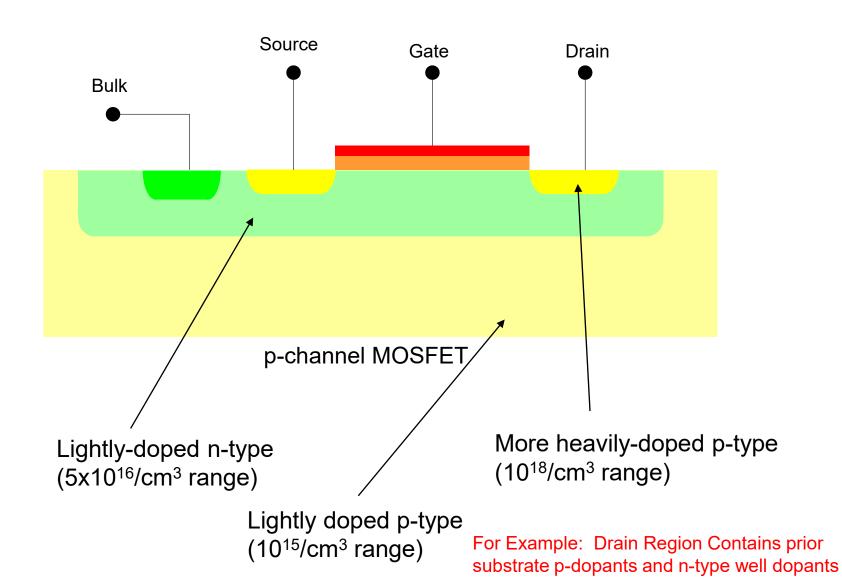


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- Vertical dimensions are not linearly depicted
- Often termed the BULK

Dominant Doping Depicted – Generally Contain Prior Lower Density Dopants of Opposite Type

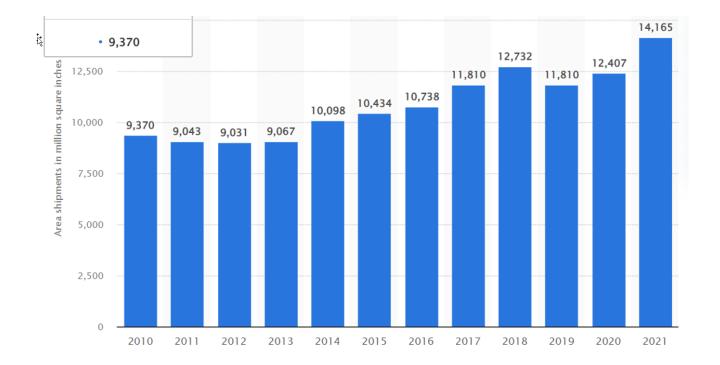


IC Fabrication Technology

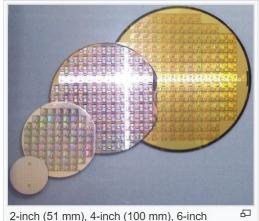
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- Large crystal is grown (pulled)
 - 12 inches (300mm) in diameter and 1 to 2 m long
 - Sliced to 250 μ m to 500 μ m thick
 - Prefer to be much thinner but thickness needed for mechanical integrity
 - 4 to 8 cm/hr pull rate
 - T=1430 °C
- Crystal is sliced to form wafers
- Cost for 12" wafer around \$200
- 5 companies provide 90% of worlds wafers
- Somewhere around 400,000 12in wafers/month

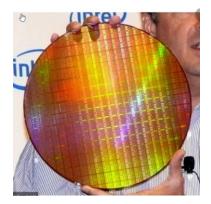
Silicon wafer area is a better metric



Wafer size ◆	Typical Thickness [♦]	Year Prodn \$ [15]	Weight per 🗢 wafer	100 mm2 [hide] (10 mm) Die per ✦ wafer
1-inch (25 mm)		1960		
2-inch (51 mm)	275 µm	<mark>1969</mark>		
3-inch (76 mm)	375 µm	1972		
4-inch (100 mm)	525 µm	1976	10 grams [19]	56
4.9 inch (125 mm)	625 µm	1981		
150 mm (5.9 inch, usually referred to as "6 inch")	675 µm	1983		
200 mm (7.9 inch, usually referred to as "8 inch")	725 µm.	1992	53 grams [19]	269
300 mm (11.8 inch, usually referred to as "12 inch")	775 µm	2002	125 grams ^[19]	640
450 mm (17.7 inch) (proposed). ^[20]	925 µm	future	342 grams ^[19]	1490
675-millimetre (26.6 in) (Theoretical). ^[21]	Unknown.	future		



(150 mm), and 8-inch (200 mm) wafers

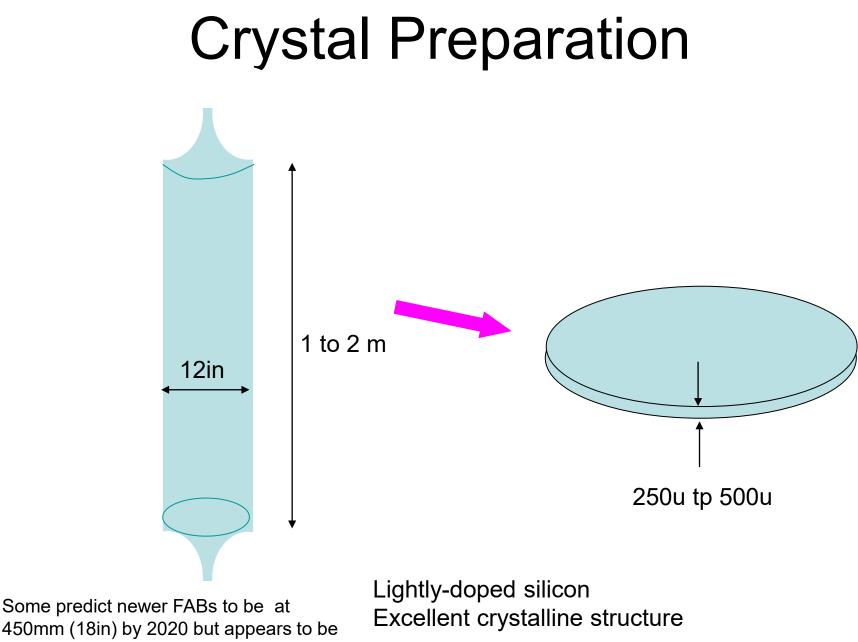


300mm wafer





450 mm wafer



450mm (18in) by 2020 but appears to be uncertain whether it will ever happen



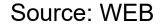
Return on Investment Essential to Make Transition

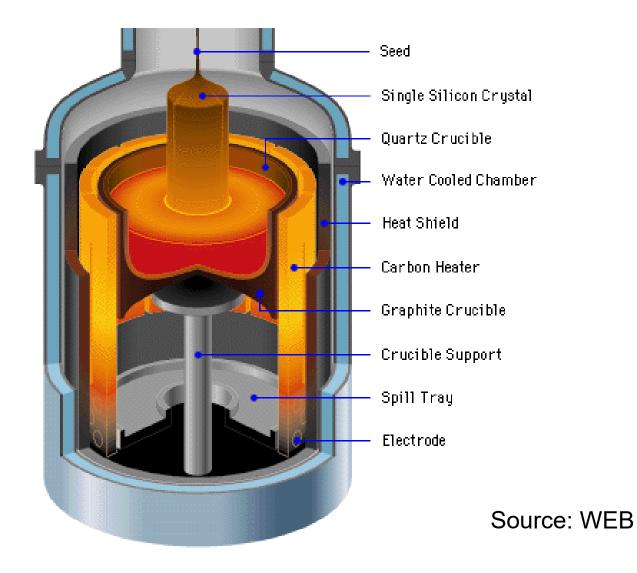
200mm (8") and 300mm (12") are dominant in production today

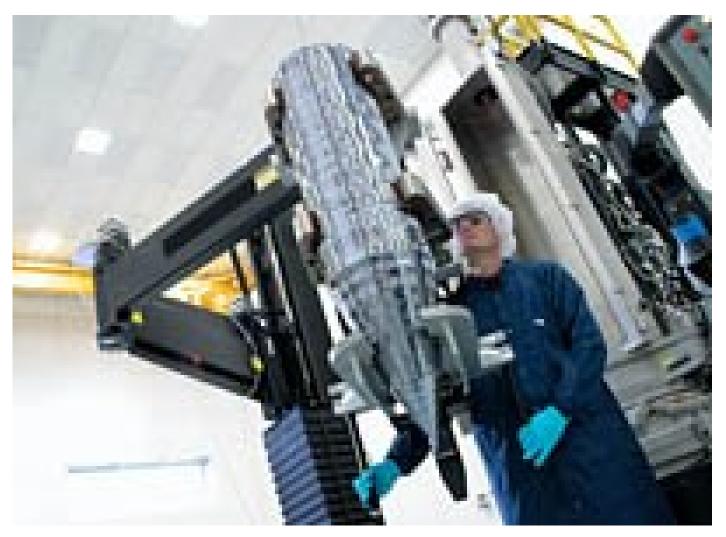


From www.infras.com









Source: WEB



A section of 300mm ingot is loaded into a wiresaw

Source: WEB



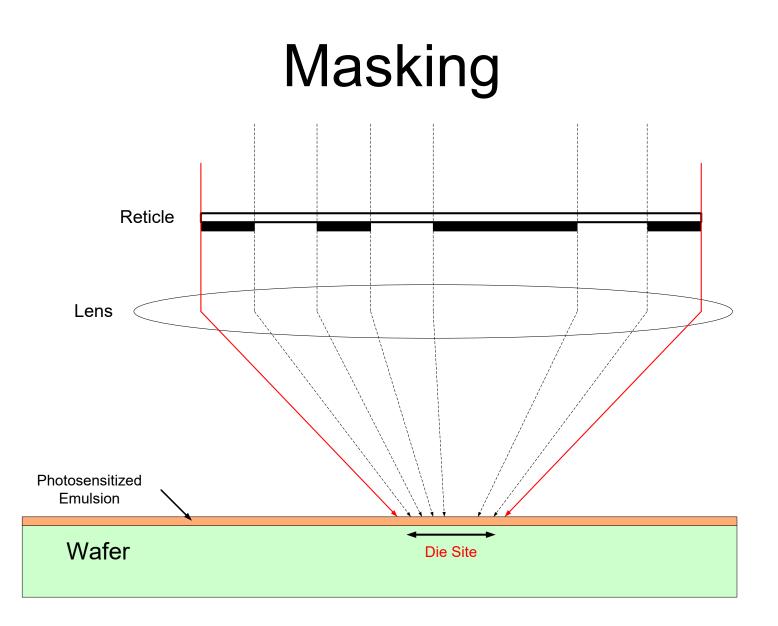
Source: WEB

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Masking

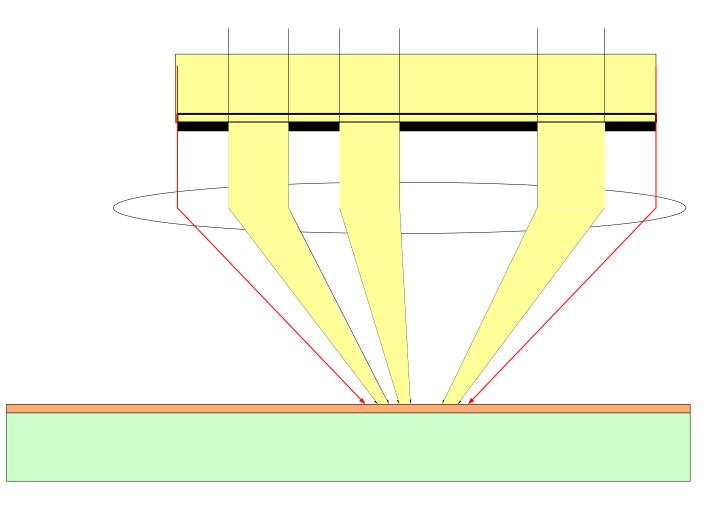
- Use masks or reticles to define features on a wafer
 - Masks same size as wafer
 - Reticles used for projection
 - Reticle much smaller (but often termed mask)
 - Reticles often of quartz with chrome
 - Quality of reticle throughout life of use is critical
 - Single IC may require 20 or more reticles
 - Cost of "mask set" now exceeds \$1million for state of the art processes
 - Average usage 500 to 1500 times
 - Mask costs exceeding 50% of total fabrication costs in sub 100nm processes
 - Serve same purpose as a negative (or positive) in a photographic process
 - Usually use 4X optical reduction exposure area approx. 860mm² (now through 2022 ITRS 2007 litho, Table LITH3a)



Step and Repeat (stepper) used to image across wafer

Masking

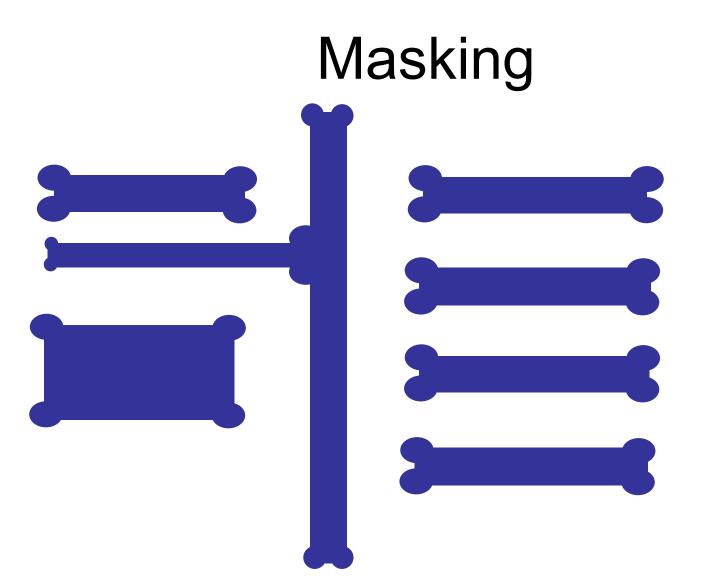
Exposure through reticle



Masking



Mask Features



Mask Features Intentionally Distorted to Compensated For Wavelength Limitations in Small Features

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Photolithographic Process

- Photoresist
 - Viscous Liquid
 - Uniform Application Critical (spinner)
 - Baked to harden
 - Approx 1u thick
 - Non-Selective
 - Types
 - Negative unexposed material removed when developed
 - · Positive-exposed material removed when developed
 - Thickness about 450nm in 90nm process (ITRS 2007 Litho)
- Exposure
 - Projection through reticle with stepper (scanners becoming popular)
 - Alignment is critical !!
 - E-Bean Exposures
 - Eliminate need fro reticle
 - Capacity very small

Stepper: Optics fixed, wafer steps in fixed increments

Scanner: Wafer steps in fixed increments and during exposure both optics and wafer are moved to increase effective reticle size

Steppers



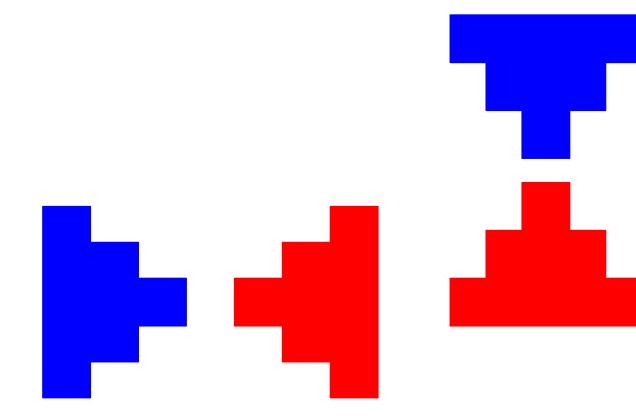
Stepper costs in the \$10M range with thru-put of around 100 wafers/hour

Steppers



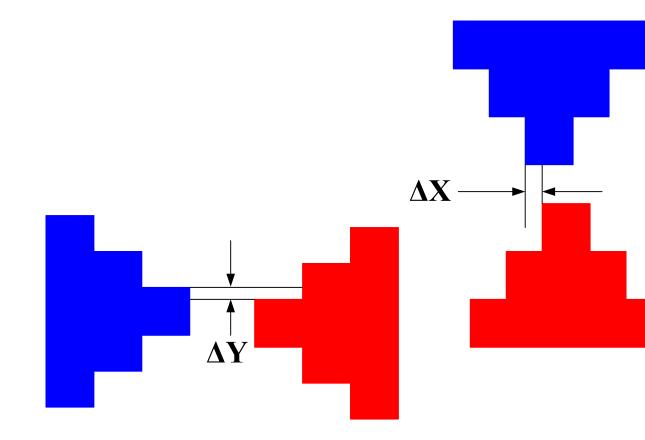
Mask Alignment

Correctly Aligned



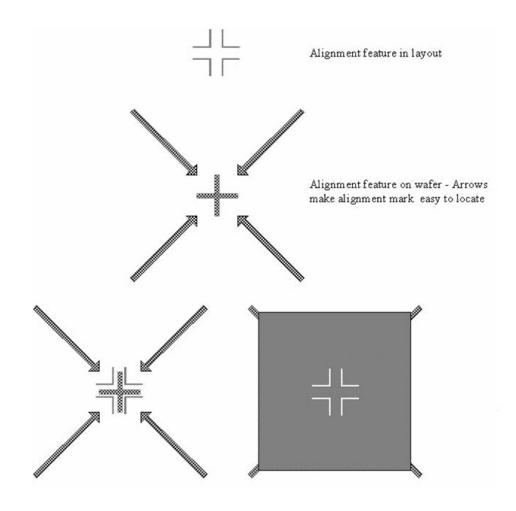
Mask Alignment

Alignment Errors



Mask Alignment

Other alignment marks (http://www.mems-exchange.org/users/masks/intro-equipment.html)



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Deposition

- Application of something to the surface of the silicon wafer or substrate
 - Layers 15A to 20u thick
- Methods
 - Physical Vapor Deposition (nonselective)
 - Evaporation/Condensation
 - Sputtering (better host integrity)
 - Chemical Vapor Deposition (nonselective)
 - Reaction of 2 or more gases with solid precipitate
 - Reduction by heating creates solid precipitate (pyrolytic)
 - Screening (selective)
 - For thick films
 - Low Tech, not widely used today

Deposition

Example: Chemical Vapor Deposition

Silane (SiH₄) is a gas (toxic and spontaneously combustible in air) at room temperature but breaks down into Si and H₂ above 400°C so can be used to deposit Si.

 $S_iH_4 \rightarrow S_i + 2H_2$

IC Fabrication Technology

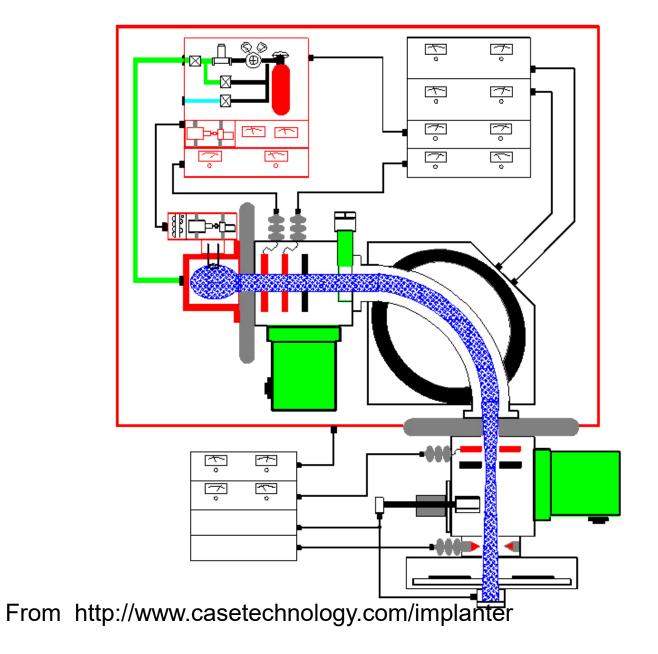
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Ion Implantation

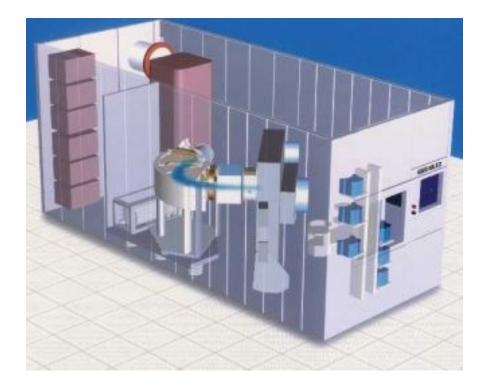
Application of impurities into the surface of the silicon wafer or substrate

- Individual atoms are first ionized (so they can be accelerated)
- Impinge on the surface and burry themselves into the upper layers
- Often very shallow but with high enough energy can go modestly deep
- Causes damage to target on impact
- Annealing heals most of the damage
- Very precise control of impurity numbers is possible
- Very high energy required
- High-end implanters considered key technology for national security

Ion Implantation Process



Ion Implanter



From http://www.casetechnology.com/implanter



Stay Safe and Stay Healthy !

End of Lecture 9